



**CYPRESS**<sup>®</sup>  
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# Military Memory

Q4 2018

## Cypress Roadmap



# Military Memory Portfolio

Military Memory | Single-Event Latch-Up Immune

	Fast Async SRAM		Sync SRAM		Nonvolatile SRAM	F-RAM™	NOR Flash	
	ECC <sup>1</sup>	NoBL <sup>2</sup> , ECC	QDR <sup>3</sup> II+/IV	Serial/Parallel I/O	Serial/Parallel I/O, ECC	Serial I/O, ECC	Parallel I/O, ECC	
64Mb-1Gb			<b>CY7C41xKV13</b> 144Mb; 667–1066 MHz, 1.3 V, x18/x36, Burst 2, M <sup>4</sup>			<b>S70/79FL-S</b> <span style="border: 1px solid green; padding: 2px;">Q119</span> 1Gb; 3.0 V, 133-MHz QSPI, Auto E, M	<b>S29GL-S</b> <span style="border: 1px solid green; padding: 2px;">Q119</span> 1Gb; 3.0 V 130ns, x16, Auto E <sup>5</sup> , M	
			<b>CYRS26xKV18</b> 144Mb, 1.8 V, 450 MHz, x18/x36, Burst 2/4, M			<b>S25FL-S</b> <span style="border: 1px solid green; padding: 2px;">Q418</span> 512Mb; 3.0 V, 133-MHz QSPI, Auto E, M	<b>S29GL-S</b> 128Mb-512Mb; 3.0 V 130ns, x16, Auto E, M	
			<b>CYPT154xAV18</b> 72Mb, 1.8 V, 250 MHz, x18/x36; Burst 2/4, M			<b>S25FL-S</b> <span style="border: 1px solid green; padding: 2px;">Q418</span> 128Mb/256Mb; 3.0 V, 133-MHz QSPI, Auto E, M	<b>S29GL-S</b> <span style="border: 1px solid green; padding: 2px;">Q119</span> 64Mb; 130 ns/15 ns, 3.0 V, x16, Auto E, M	
1Mb-36Mb	<b>CY7S106x</b> 16Mb, 1.8–5.0 V, 10 ns, x8/x16/x32, Auto E, M	<b>CY7C144/6xK</b> 36Mb, 133–250 MHz, 2.5 V/3.3 V, x18/x36, M		<b>CY14B116x</b> 16Mb; 1.8–3.0 V, 25 ns/45 ns x8/x16/x32, M, RTC <sup>6</sup>	<b>CY15B102N</b> 2Mb, 2.0–3.6 V, 60 ns, x16, Auto E, M			
	<b>CY7S105x</b> 8Mb, 1.8–5.0 V, 10 ns, x8/x16/x32, Auto E, M	<b>CY7C137/8xK</b> 18Mb, 100–250 MHz, 2.5 V/3.3 V, x18/x36, M		<b>CY14B104x</b> 4Mb, 1.8–3.0 V, 25 ns/45 ns x8/x16, Auto E, M	<b>CY15B102Q</b> <span style="border: 1px solid green; padding: 2px;">Q418</span> 2Mb, 2.0–3.6 V, 40-MHz SPI, Auto E, M			
	<b>CY7S104x</b> 4Mb, 1.8–5.0 V, 12 ns, x8/x16, Auto E, M	<b>CY7C136xK</b> 9Mb, 100–250 MHz, 2.5 V/3.3 V, x18/x36, M		<b>CY14B101x</b> 1Mb, 1.8–3.0 V, 25 ns/45 ns x8/x16, SPI, Auto E, M, RTC	<b>FM25V10</b> 1Mb; 2.0–3.6 V, 40-MHz SPI, Auto E, M			
64Kb-256Kb				<b>STK14CA8C</b> <span style="border: 1px solid green; padding: 2px;">Q418</span> 1Mb; 3.3 V/5.0 V, 35 ns, x8; QML-Q <sup>7</sup>				
				<b>STK14C88C</b> <span style="border: 1px solid green; padding: 2px;">Q418</span> 256Kb; 3.0 V/5.0 V, 35 ns, x8; QML-Q				

<sup>1</sup> Error-correcting code

<sup>2</sup> No Bus Latency

<sup>3</sup> Quad Data Rate

<sup>4</sup> Military Temperature: -55°C to +125°C

<sup>5</sup> AEC-Q100 -40°C to +125°C

<sup>6</sup> Real-time clock

<sup>7</sup> Qualified Manufacturers List Level Q, per MIL-PRF-38535

Status Availability

EOL (Last-Time-Ship)

Concept
  Development
  Sampling
  Production

QYY
QYY
QYY

# 256Kb/1Mb Military nvSRAM

## Applications

Military communication and real-time controls, avionics real-time controls and high-reliability data logging

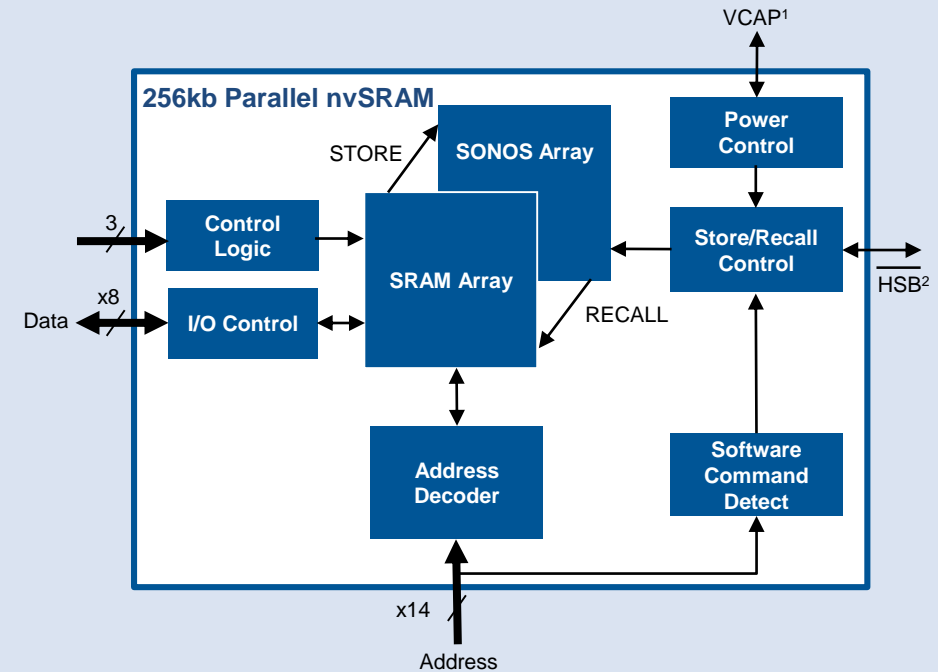
## Features

- **Fast Nonvolatile Memory**
  - Access time 35 ns
  - Available in parallel interface for 256Kb and 1Mb densities
  - Unlimited read/write endurance
  - One million store cycles on power fail
- **Specifications**
  - 100 years data retention at +85°C
  - Qualified Manufacturers List Level Q (QML-Q certified) per MIL-PRF-38535
  - Military temperature grade: -55°C to +125°C
- **Packages: Ceramic 32-pin DIP**

## Collateral

Preliminary Datasheet: [Contact Sales](#) (Available Now)

## STK14C88: 256Kb nvSRAM



## Availability

Sampling: Now  
Production: Q418

<sup>1</sup> External capacitor connection

<sup>2</sup> Hardware STORE busy

# 72Mb QDR<sup>®1</sup>-II+ SRAM

## Applications

Payload processing and reconfigurable computing platforms

## Features

- **High Performance Memory**
  - Maximum frequency of operation/throughput: 250 MHz/36 Gbps
  - Two independent unidirectional data ports for read and write enable concurrent transactions
  - Maximum throughput with double data rate (DDR) data ports
  - Output impedance matching input (ZQ): Matches the device outputs to system data bus impedance
  - Bit-interleaving to eliminate multi-bit errors
  - I/O signaling standards: 1.5–1.8 V (HSTL)
- **Specifications**
  - Burst sizes: 2 or 4
  - Bus-width configurations: x18 or x36
  - Military temperature grade: -55°C to +125°C
- **Controllers available for Altera/Xilinx/Microsemi FPGAs**
- **Package: 165-pin CCGA<sup>2</sup>**

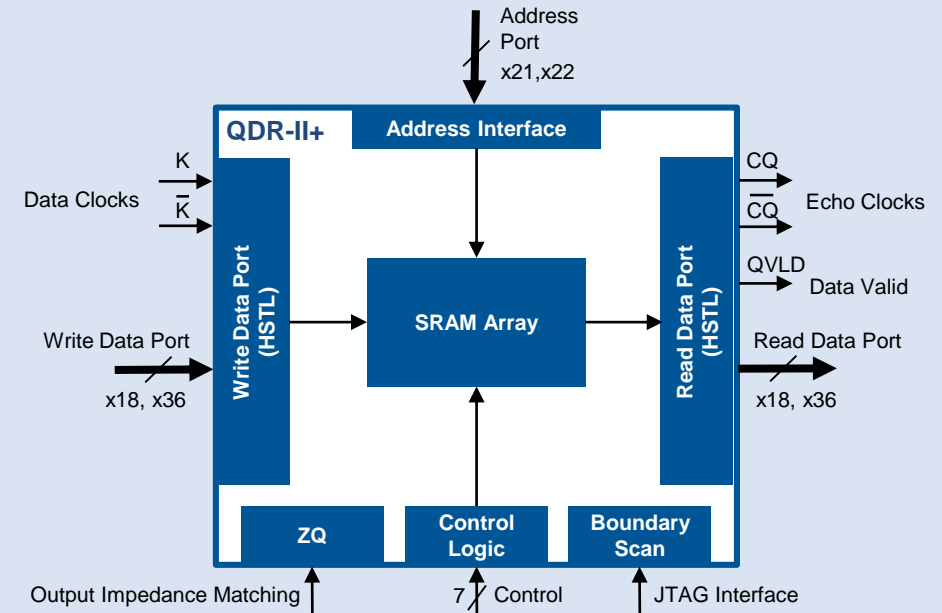
## Collateral

**Datasheets:** [CYPT1542AV18/CYPT1544AV18](#)  
[CYPT1543AV18/CYPT1545AV18](#)

<sup>1</sup> Quad Data Rate: Four data transfers per clock cycle

<sup>2</sup> Ceramic column grid array package

## CYPT154XAV18: Military QDR<sup>®II+</sup> SRAM



## Availability

**Sampling:** Now  
**Production:** Now

# QDR®-IV SRAM

## Applications

Switches and routers, high-performance computing, test equipment, military and aerospace systems

## Features

### Highest Performance Memory

- Available in two options: High Performance (RTR 1334 MT/s) and Extreme Performance (RTR 2132 MT/s)
- Two independent, bidirectional double data rate (DDR)<sup>1</sup> data ports
- Error-correcting code (ECC) to detect and correct single-bit errors (<0.01 FIT/Mb<sup>2</sup>)
- On-die termination (ODT) to reduce board complexity
- De-skew training<sup>3</sup> to improve signal-capture timing

### Specifications

- I/O Levels: 1.2–1.25 V (HSTL/SSTL) and 1.1–1.2 V (POD<sup>4</sup>)
- Bus-width configurations: x18 and x36
- Industrial and commercial temperature grades
- Military temperature grade: -55°C to +125°C

### RoHS<sup>5</sup>-Compliant Package

### Package: 361-ball flip-chip ball grid array (FCBGA)

## Collateral

Datasheets: [CY7C4021KV13/CY7C4041KV13](#)

<sup>1</sup> Two data transfers per clock cycle

<sup>2</sup> The projected failure rate of a device. One FIT/Mb equals one failure per billion device hours per megabit of data

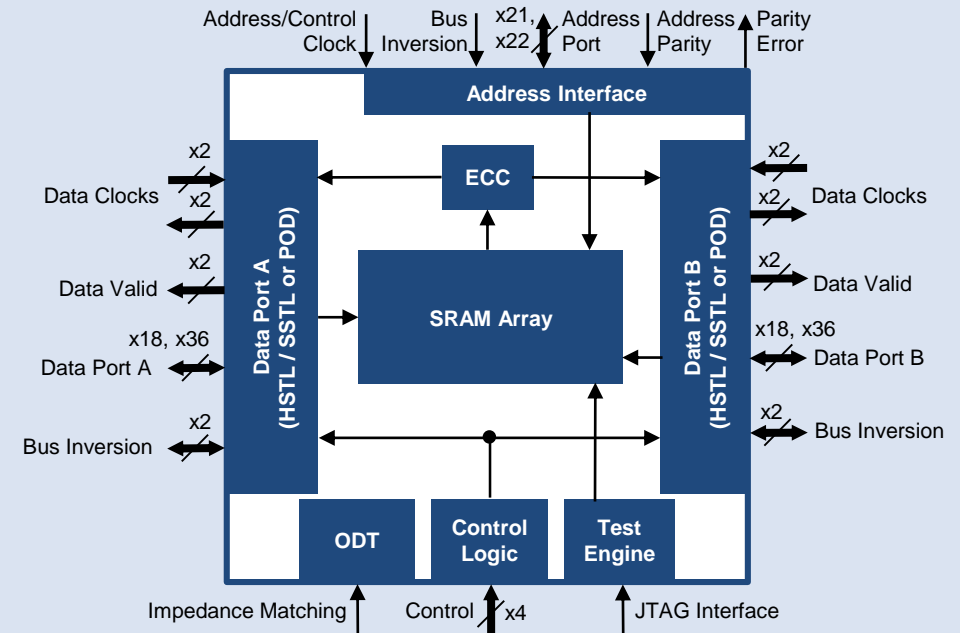
<sup>3</sup> An iterative algorithm for assessing and eliminating the skew (differences in arrival times) between data signals

<sup>4</sup> Pseudo open drain: Signaling interface that uses strong pull-down and weak pull-up

## Family Table

Option	Density	MPN	Maximum Frequency	RTR
QDR-IV HP	72Mb 144Mb	CY7C40x1KV13 CY7C41x1KV13	667 MHz	1,334 MT/s
QDR-IV XP	72Mb 144Mb	CY7C40x2KV13 CY7C41x2KV13	1,066 MHz	2,132 MT/s

## QDR-IV



## Availability

Production: Now

# Synchronous SRAM with On-Chip ECC

## Applications

Switches and routers, radar and signal processing, test equipment, automotive, military and aerospace systems

## Features

### New Features

- Available in two modes<sup>1</sup>: Pipeline and Flow-Through
- SCD and DCD deselect options<sup>2</sup>
- Error-correcting code (ECC) to detect and correct single-bit errors

### Specifications

- Voltage options: 2.5 V and 3.3 V
- Bus-width configurations: x18 and x36
- Industrial and commercial temperature grades
- Military temperature grade: -55°C to +125°C

### Packages: 165-ball BGA (w/ and w/o leaded balls) and 100-pin TQFP

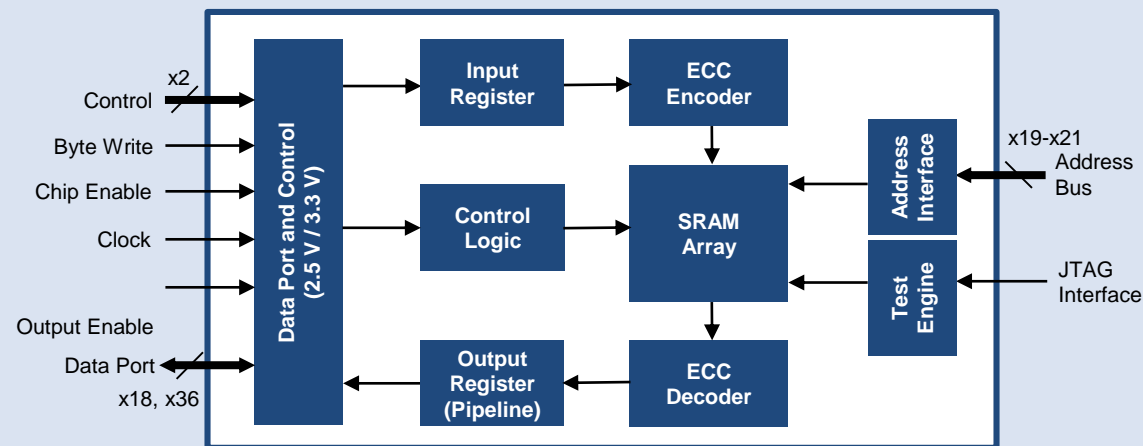
## Collateral

**Datasheets:** [CY7C135XKV33/CY7C136XKV33](#)  
[CY7C137XKV33/CY7C138XKV33](#)  
[CY7C144XKV33/CY7C146XKV33](#)

## Family Table

Option	Density	MPN	RTR	FIT/Mb <sup>3</sup>
Standard Sync with ECC Pipeline	9Mb 18Mb 36Mb	CY7C1360/2K CY7C1370/2K CY7C1440/2K	250 MT/s	<0.01
Standard Sync with ECC Flow-Through	9Mb 18Mb 36Mb	CY7C1361/3K CY7C1371/3K CY7C1441/3K	133 MT/s	<0.01

## Synchronous SRAM with ECC



## Availability

**Production:** Now

<sup>1</sup> Modes of synchronous SRAM operation that optimize either read latency (Flow-Through) or operating frequency (Pipeline)

<sup>2</sup> Modes of operation in Pipeline mode where the output driver is tri-stated after either a single cycle (SCD) or dual cycle (DCD) of issuing the deselect command

<sup>3</sup> The projected failure rate of a device. One FIT/Mb equals one failure per billion device hours per megabit of data

# Fast SRAM Family with PowerSnooze<sup>1</sup>

## Applications

Programmable logic controller, handheld devices, multifunction printers, computation servers and automotive

## Features

- **Error Detection and Correction**
  - Error-correcting code (ECC) logic to detect and correct single-bit errors
  - Bit-interleaving to avoid multi-bit errors
  - Error Indication (ERR) pin to indicate single-bit errors
- **Specifications**
  - Access time: 10 ns
  - Deep-sleep current: 15  $\mu$ A for 4Mb
  - Bus-width configurations: x8, x16, and x32
  - Industrial and automotive temperature grades
  - Military temperature grade: -55°C to +125°C
- **Packages: 48-ball BGA (w/ and w/o leaded balls)**

## Collateral

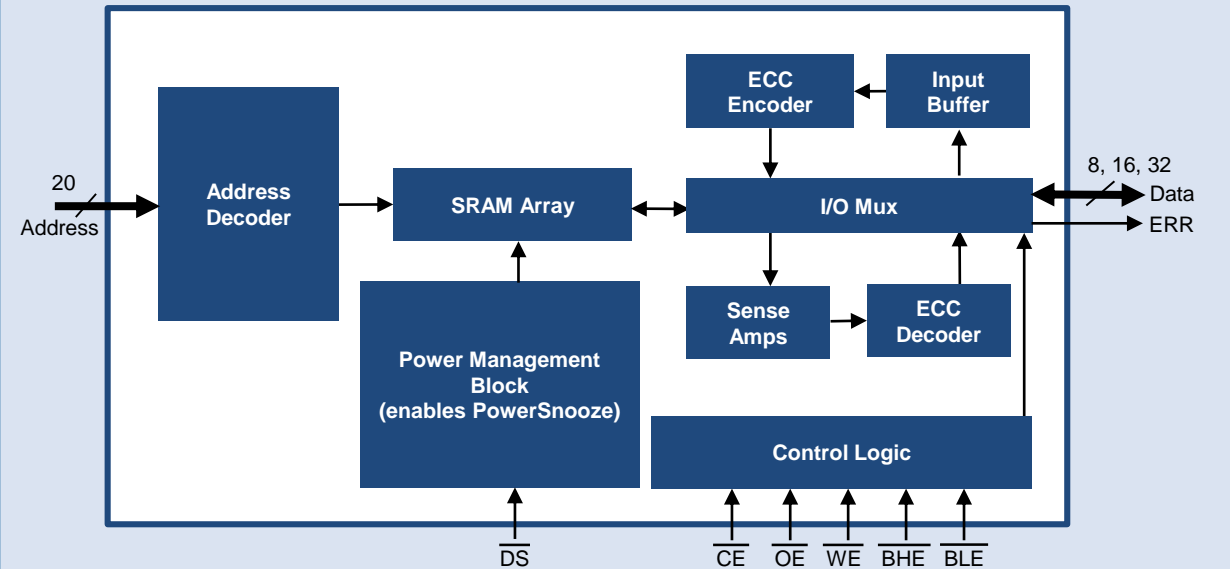
**Datasheets:** [CY7S1049G/CY7C1049G](#)  
[CY7S1059H/CY7C1059H](#)  
[CY7S1069G/CY7C1069G](#)

<sup>1</sup> A Fast SRAM with a deep-sleep mode in addition to a conventional standby mode

## Family Table

Density	MPN	Access Time	Deep Sleep Current (maximum at 85°C)
4Mb	CY7S104x	10 ns	15 $\mu$ A
8Mb	CY7S105x	10 ns	22 $\mu$ A
16Mb	CY7S106x	10 ns	22 $\mu$ A

## Fast SRAM with PowerSnooze



## Availability

**Sampling:** Now  
**Production:** Now

# 16Mb Parallel nvSRAM

## Applications

Industrial automation, programmable logic controllers, gaming machines, industrial data logging, telecom equipment, networking and storage

## Features

### Fast Nonvolatile Memory

- Access time (25 ns)
- Optional real-time clock (RTC) functionality
- Available in parallel and open NAND Flash Interface (ONFI) Version 1.0 interfaces
- Unlimited read/write endurance
- One million store cycles on power fail

### Specifications

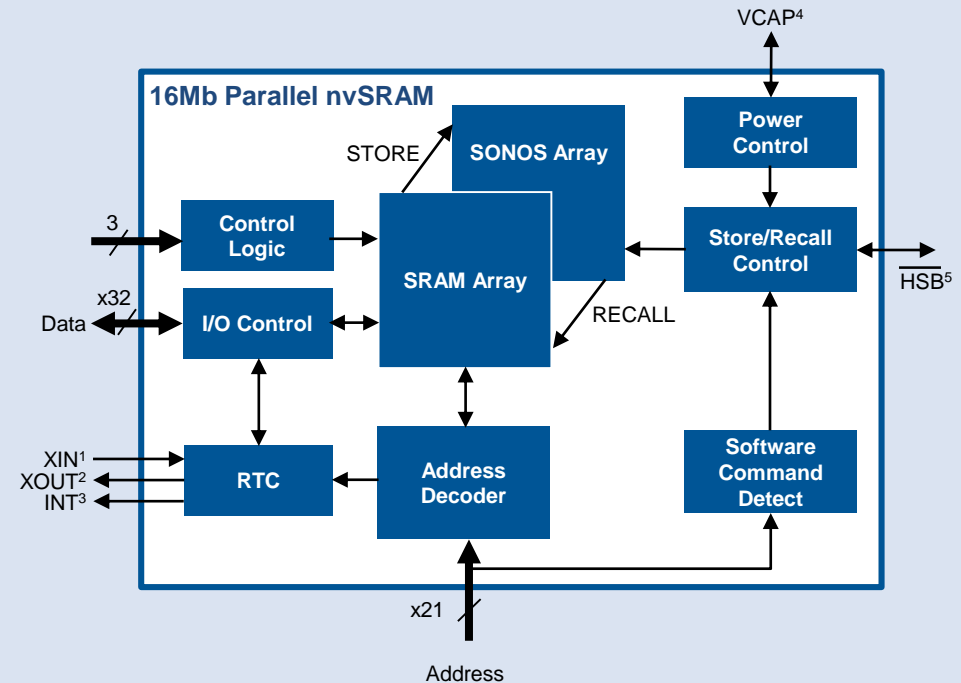
- 100 years data retention at +85°C
- Military temperature grade: -55°C to +125°C

- Packages: 44-pin TSOP, 54-pin TSOP, 165-ball BGA (w/ and w/o leaded balls)

## Collateral

Datasheet: [CY14X116L/CY14X116N/CY14X116S](#)

## CY14B116: 16Mb nvSRAM



## Availability

Sampling: Now  
Production: [Contact Sales](#)

<sup>1</sup> Crystal connection input

<sup>2</sup> Crystal connection output

<sup>3</sup> Interrupt output/calibration/square wave

<sup>4</sup> External capacitor connection

<sup>5</sup> Hardware STORE busy



# 2Mb Military SPI F-RAM

## Applications

Multifunction printers, industrial controls and automation, medical wearables, test and measurement equipment, smart meters, aerospace and defense applications, missiles and launchers

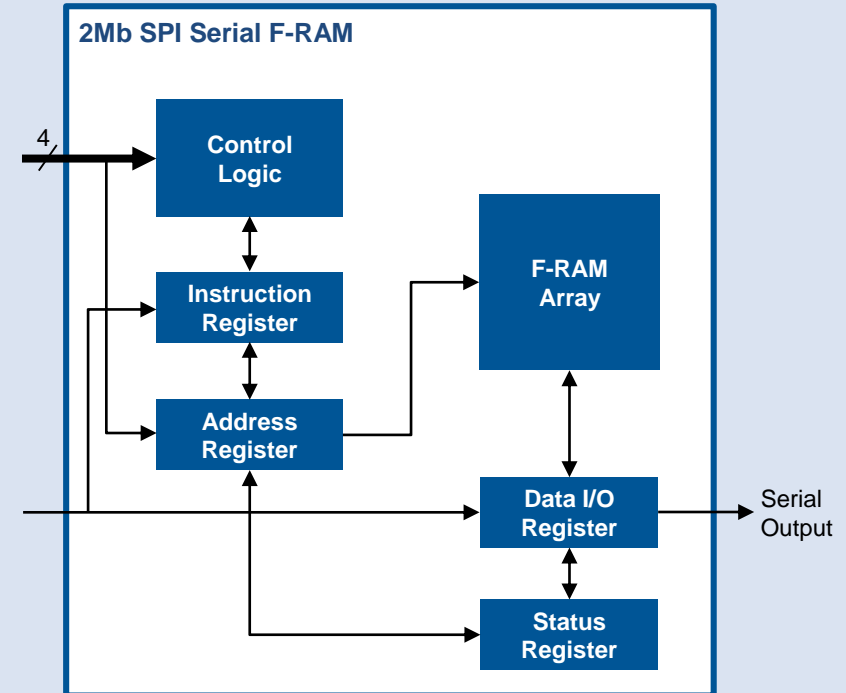
## Features

- **Ultra-Low Power Memory**
  - 40-MHz SPI interface
  - 100-trillion read/write cycle endurance
- **Specifications**
  - Operating voltage range: 2.0–3.6 V
  - Low (20- $\mu$ A) sleep current at +125°C
  - 100 years data retention at +85°C
  - Military temperature grade: -55°C to +125°C
- **Packages: 8-pin TDFN and 8-pin SOIC**

## Collateral

Datasheet: [CY15B102Q](#)

## CY15B102Q: 2Mb SPI F-RAM



## Availability

**Sampling:** Now  
**Production:** Q418

# 64Mb/128Mb/256Mb/512Mb/1Gb Parallel NOR Flash

## Applications

Military systems boot memory  
Avionics boot memory

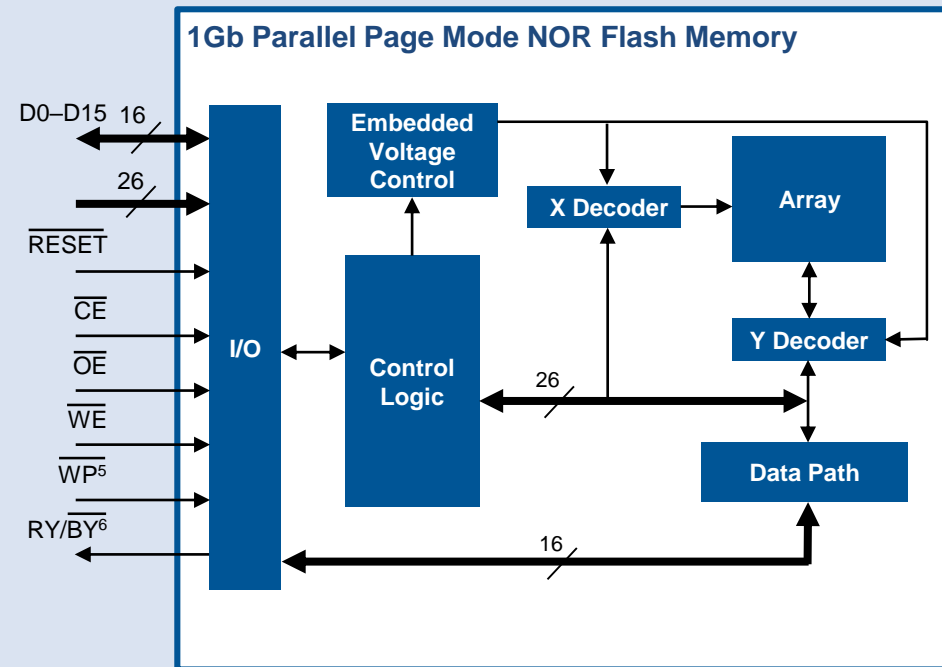
## Features

- **High-Reliability Boot Flash Memory**
  - 100 program<sup>1</sup>/sector erase<sup>2</sup> endurance cycles<sup>3</sup> at +125°C
  - >10 years data retention at +125°C
- **Specifications**
  - Operating voltage range: 2.7–3.6 V
  - Initial access time: 120 ns
  - Page access time: 15 ns
  - Program time (512B): 0.4 ms (typical)
  - Sector erase time (128KB): 410 ms (typical)
  - Military temperature grade: -55°C to +125°C
- **Packages: 64-ball fortified<sup>4</sup> BGA (9 x 9 mm and 13 x 11 mm, w/ and w/o leaded balls)**

## Collateral

Datasheet: [S29GLXXXS](#) (128M/256M/512M/1G)

## S29GLXXXS: Parallel NOR Flash



## Availability

Samples: Now

Production: Now (128Mb/256Mb/512Mb) / Q1'19 (1Gb) / Q1'19 (64Mb)

<sup>1</sup> The operation required to change a NOR Flash memory cell state from "1" to "0"

<sup>2</sup> The operation in which all the bytes in a sector of NOR Flash memory are erased simultaneously prior to programming

<sup>3</sup> The number of times a NOR Flash memory sector can be programmed or erased before it wears out

<sup>4</sup> Fortified BGA supports a 1-mm ball pitch

<sup>5</sup> Write protect input

<sup>6</sup> Ready/busy output

# 128Mb/256Mb/512Mb/1Gb SPI NOR Flash

## Applications

Military systems boot memory  
Avionics boot memory

## Features

- **High-Reliability Boot Flash Memory**
  - 100 program<sup>1</sup>/sector erase<sup>2</sup> endurance cycles<sup>3</sup> at +125°C
  - >10 years data retention at +125°C
- **Specifications**
  - Operating voltage range: 2.7–3.6 V
  - Single data rate (SDR)<sup>4</sup> clock rate: 104-MHz quad input/output (QIO)<sup>5</sup>
  - Double data rate (DDR)<sup>6</sup> clock rate: 80-MHz QIO
  - Program time (512B): 0.340 ms (typical)
  - Sector erase time (256KB): 520 ms (typical)
  - Military temperature grade: -55°C to +125°C
- **Packages: 24-ball BGA (6 x 8 mm, w/ and w/o leaded balls)**

## Collateral

Datasheets: [S25FL512S](#) (512Mb)  
[S25FL128/256S](#) (128Mb/256Mb)

<sup>1</sup> The operation required to change a NOR Flash memory cell state from “1” to “0”

<sup>2</sup> The operation in which all the bytes in a sector of NOR flash memory are erased simultaneously

<sup>3</sup> The number of times a NOR Flash memory sector can be programmed/erased before it wears out

<sup>4</sup> A mode of data transfer in which data is transferred once per clock cycle

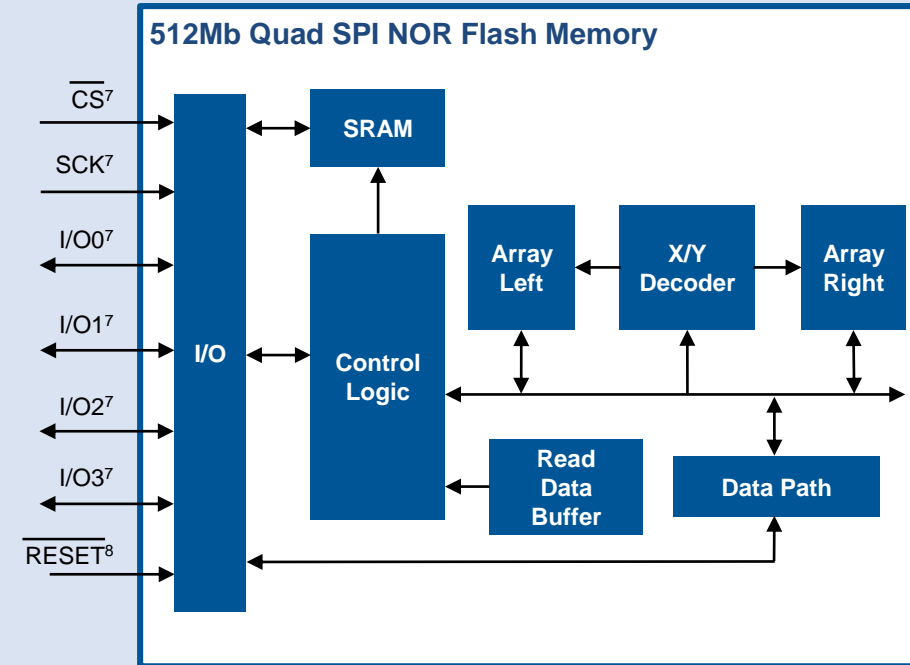
<sup>5</sup> An interface that transfers addresses or data on four I/O's simultaneously

<sup>6</sup> A mode of data transfer in which data is transferred twice per clock cycle

<sup>7</sup> Signals used for standard Quad (x4) SPI interface. Refer to the [S25FL512S](#) datasheet for signal definitions in the x1 and x2 mode.

<sup>8</sup> RESET# is an optional signal available on 16-pin-SOIC and BGA packages

## S25/70/79FLXXS: 512Mb QSPI NOR Flash



## Availability

**Sampling:** Now

**Production:** Q418 (128/256/512Mb)/Q1'19 (1Gb)



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